

Wireless Components ECTRONIC

ASK/FSK Single Conversion Receiver TDA 5210 Version 3.0

Specification May 2001

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Product Info

Product Info

General Description

The IC is a very low power consumption single chip FSK/ASK Superheterodyne Receiver (SHR) for the frequency bands 810 to 870 MHz and 400 to 440 MHz that is pin compatible with the ASK Receiver TDA5200. The IC offers a high level of integration and needs only a few external components. The device contains a low noise amplifier (LNA), a double balanced mixer, a fully integrated VCO, a PLL synthesiser, a crystal oscillator, a limiter with RSSI generator, a PLL FSK demodulator, a data filter, a data comparator (slicer) and a peak detector. Additionally there is a power down feature to save battery life.

Package



Features

- Low supply current (typ. at 868MHz I_s = 5.9mA in FSK mode, I_s = 5.2mA in ASK mode)
- Supply voltage range 5V ±10%
- Power down mode with very low supply current (50nA typ)
- FSK and ASK demodulation capability
- Fully integrated VCO and PLL Synthesiser
- ASK sensitivity < -107dBm

- Selectable frequency ranges 810-870 MHz and 400-440 MHz
- Limiter with RSSI generation, operating at 10.7MHz
- Selectable reference frequency
- 2nd order low pass data filter with external capacitors
- Data slicer with self-adjusting threshold
- FSK sensitivity <-100dBm

Application

- Keyless Entry Systems
- Remote Control Systems
- Alarm Systems
 - Low Bitrate Communication Systems

Ordering Information

Туре	Ordering Code	Package
TDA 5210	Q67037-A1100	P-TSSOP-28-1
samples available on tape and reel		

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Product Description

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2.1 Overview

The IC is a very low power consumption single chip FSK/ASK Superheterodyne Receiver (SHR) for the frequency bands 810 to 870 MHz and 400 to 440 MHz that is pin compatible with the ASK Receiver TDA5200. The IC offers a high level of integration and needs only a few external components. The device contains a low noise amplifier (LNA), a double balanced mixer, a fully integrated VCO, a PLL synthesiser, a crystal oscillator, a limiter with RSSI generator, a PLL FSK demodulator, a data filter, a data comparator (slicer) and a peak detector. Additionally there is a power down feature to save battery life.

2.2 Application

- Keyless Entry Systems
- Remote Control Systems
- Alarm Systems
- Low Bitrate Communication Systems

2.3 Features

- Low supply current (at 868MHz I_s = 5.9 mA typ. FSK mode, 5.2mA typ. ASK mode)
- Supply voltage range 5V ±10%
- Power down mode with very low supply current (50nA typ)
- FSK and ASK demodulation capability
- Fully integrated VCO and PLL Synthesiser
- RF input sensitivity ASK < -107dBm</p>
- RF input sensitivity FSK < -100dBm
- Selectable frequency ranges 810-870 MHz and 400-440 MHz
- Selectable reference frequency
- Limiter with RSSI generation, operating at 10.7MHz
- 2nd order low pass data filter with external capacitors
- Data slicer with self-adjusting threshold



2.4 Package Outlines

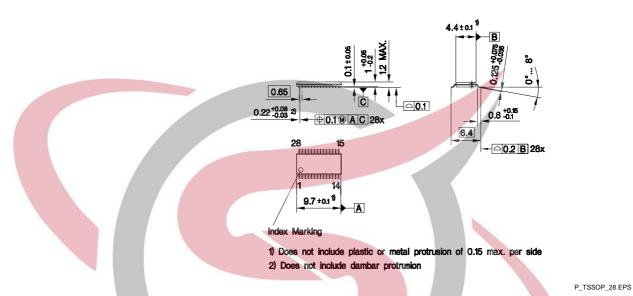


Figure 2-1 P-TSSOP-28-1 package outlines

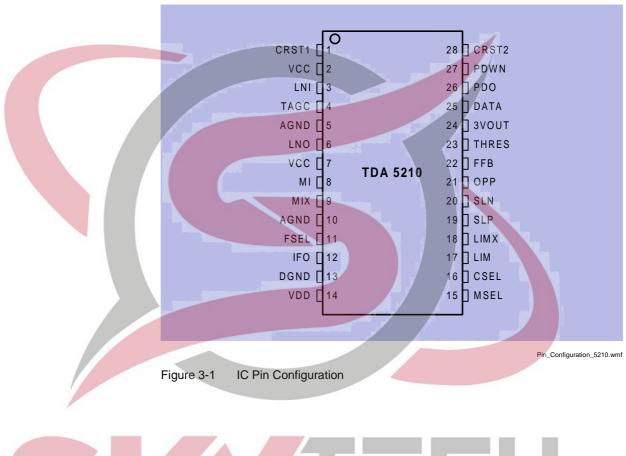


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3.1 Pin Configuration





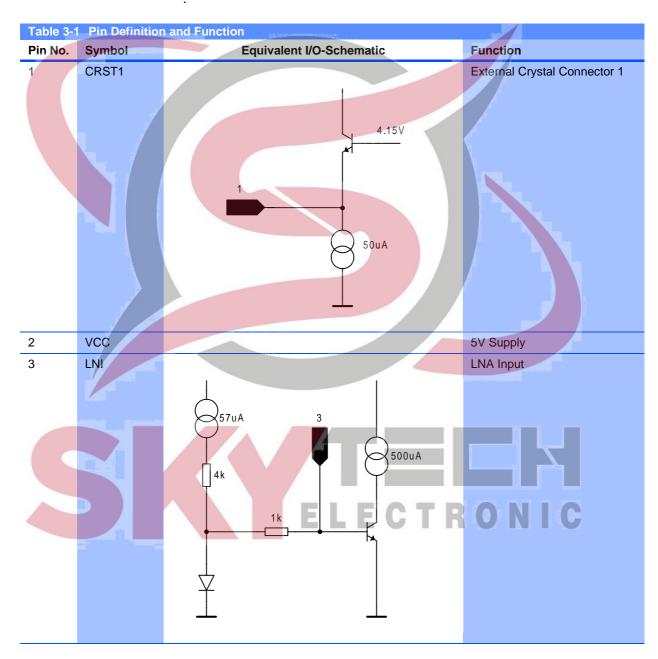




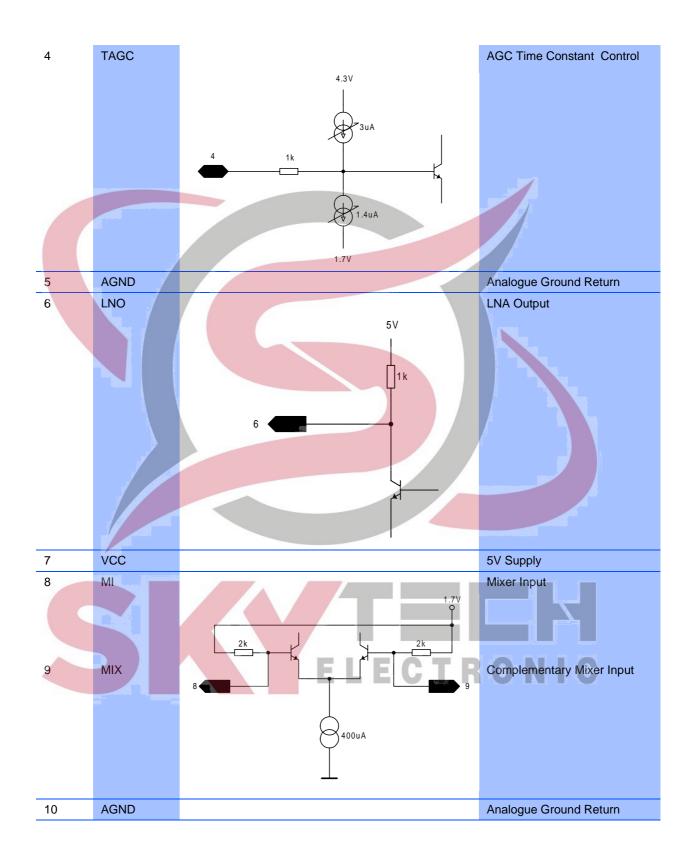
3.2 Pin Definition and Function

In the subsequent table the internal circuits connected to the pins of the device are shown. ESD-protection circuits are omitted to ease reading.

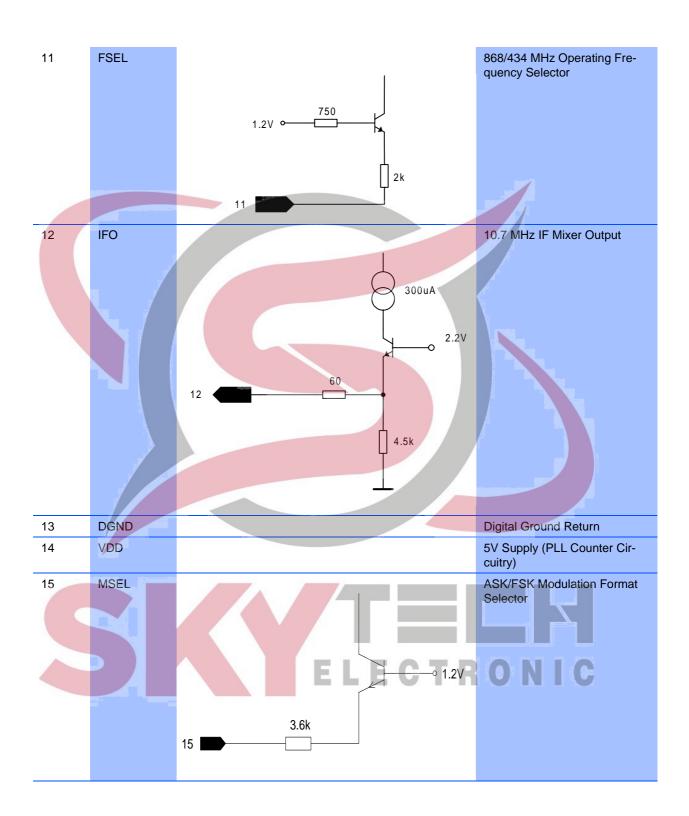




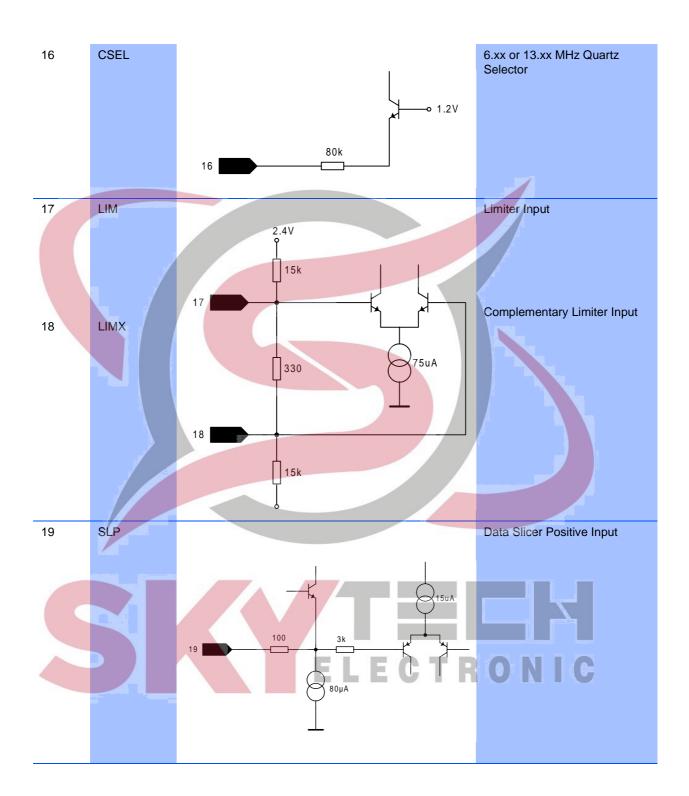




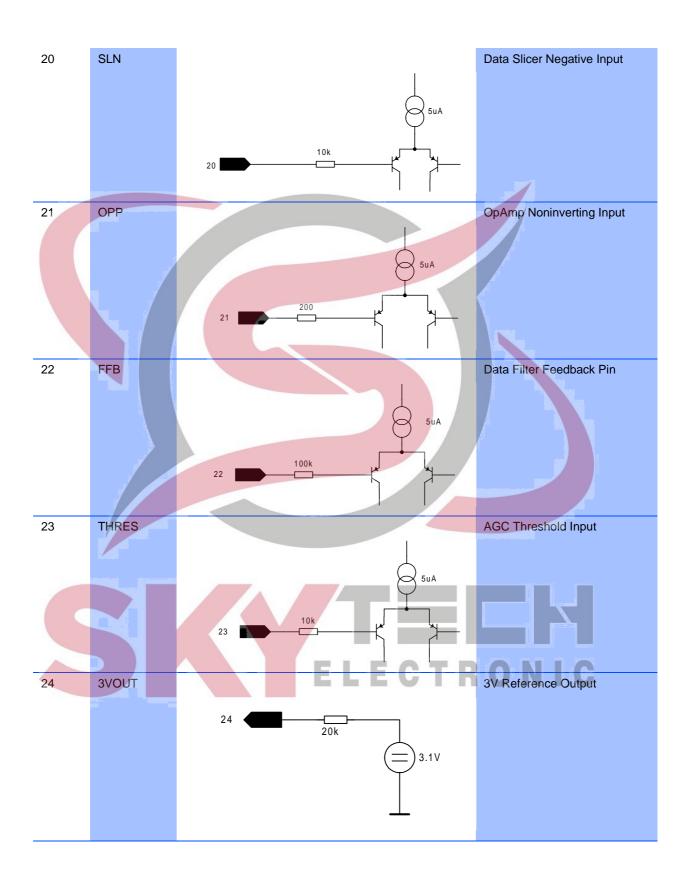




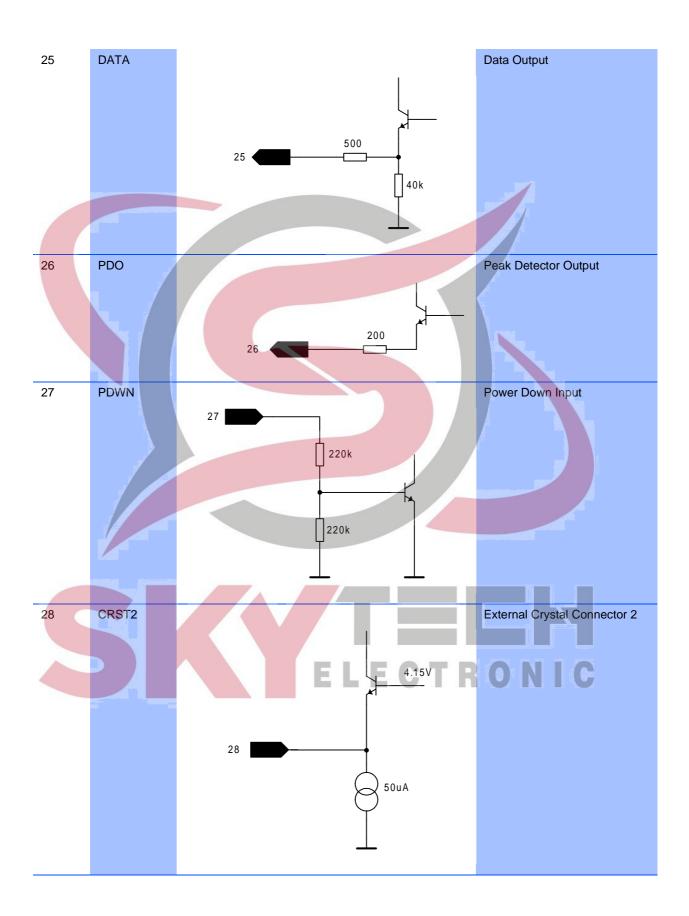






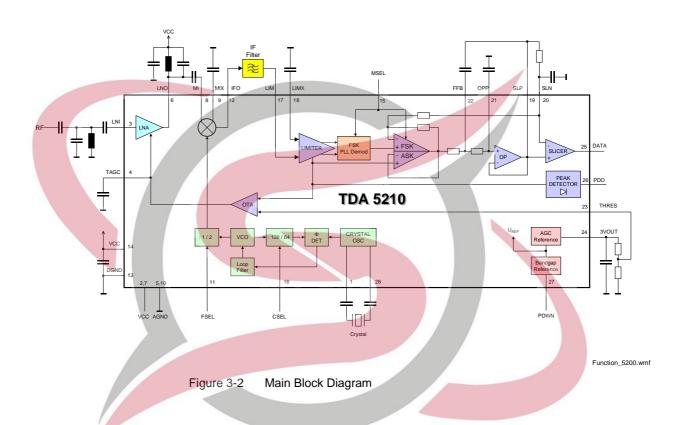








3.3 Functional Block Diagram



3.4 Functional Blocks

3.4.1 Low Noise Amplifier (LNA)

The LNA is an on-chip cascode amplifier with a voltage gain of 15 to 20dB. The gain figure is determined by the external matching networks situated ahead of LNA and between the LNA output LNO (Pin 6) and the Mixer Inputs MI and MIX (Pins 8 and 9). The noise figure of the LNA is approximately 3dB, the current consumption is 500µA. The gain can be reduced by approximately 18dB. The switching point of this AGC action can be determined externally by applying a threshold voltage at the THRES pin (Pin 23). This voltage is compared internally with the received signal (RSSI) level generated by the limiter circuitry. In case that the RSSI level is higher than the threshold voltage the LNA gain is reduced and vice versa. The threshold voltage can be generated by attaching a voltage divider between the **3VOUT** pin (Pin 24) which provides a temperature stable 3V output generated from the internal bandgap voltage and the **THRES** pin as described in Section 4.1. The time constant of the AGC action can be deter-

mined by connecting a capacitor to the **TAGC** pin (Pin 4) and should be chosen along with the appropriate threshold voltage according to the intended operating case and interference scenario to be expected during operation. The optimum choice of AGC time constant and the threshold voltage is described in Section 4.1.

3.4.2 Mixer

The Double Balanced Mixer downconverts the input frequency (RF) in the range of 400-440MHz/810-870MHz to the intermediate frequency (IF) at 10.7MHz with a voltage gain of approximately 21dB by utilising either high- or low-side injection of the local oscillator signal. In case the mixer is interfaced only single-ended, the unused mixer input has to be tied to ground via a capacitor. The mixer is followed by a low pass filter with a corner frequency of 20MHz in order to suppress RF signals to appear at the IF output (IFO pin). The IF output is internally consisting of an emitter follower that has a source impedance of approximately 330 Ω to facilitate interfacing the pin directly to a standard 10.7MHz ceramic filter without additional matching circuitry.

3.4.3 PLL Synthesizer

The Phase Locked Loop synthesiser consists of a VCO, an asynchronous divider chain, a phase detector with charge pump and a loop filter and is fully implemented on-chip. The VCO is including on-chip spiral inductors and varactor diodes. It's nominal centre frequency is 840MHz, the operating range guaranteed over the temperature range specified is 820 to 860MHz. Depending on whether high- or low-side injection of the local oscillator is used the receive frequency ranges are 810 to 840 and 840 to 870MHz or 400 to 420 and 420 to 440MHz (see also Section 4.4). No additional external components are necessary.

The oscillator signal is fed both to the synthesiser divider chain and to the down-converting mixer. In case of operation in the 400 to 440 MHz range, the signal is divided by two before it is fed to the mixer. This is controlled by the selection pin FSEL (Pin 11) as described in the following table. The overall division ratio of the divider chain can be selected to be either 128 or 64, depending on the frequency of the reference oscillator quartz (see below and Section 4.4). The loop filter is also realised fully on-chip.

Table 3-2 FSEL Pin Operating States	
FSEL	RF Frequency
Open	400-440 MHz
Shorted to ground	810-870 MHz



3.4.4 Crystal Oscillator

The on-chip crystal oscillator circuitry allows for utilisation of quartzes both in the 6 and 13MHz range as the overall division ratio of the PLL can be switched between 64 and 128 via the **CSEL** (Pin 16) pin according to the following table.

Table 3-3 CSEL Pin Operating States	
CSEL	Crystal Frequency
Open	6.xx MHz
Shorted to ground	13.xx MHz

The calculation of the value of the necessary quartz load capacitance is shown in Section 4.3, the quartz frequency calculation is explained in Section 4.4.

3.4.5 Limiter

The Limiter is an AC coupled multistage amplifier with a cumulative gain of approximately 80 dB that has a bandpass-characteristic centred around 10.7 MHz. It has a typical input impedance of 330 Ω to allow for easy interfacing to a 10.7 MHz ceramic IF filter. The limiter circuit also acts as a Receive Signal Strength Indicator (RSSI) generator which produces a DC voltage that is directly proportional to the input signal level as can be seen in Figure 4-2. This signal is used to demodulate ASK-modulated receive signals in the subsequent baseband circuitry. The RSSI output is applied to the modulation format switch, to the Peak Detector input and to the AGC circuitry.

In order to demodulate ASK signals the MSEL pin has to be left open as described in the next chapter.

3.4.6 FSK Demodulator

To demodulate frequency shift keyed (FSK) signals a PLL circuit is used that is contained fully on chip. The Limiter output differential signal is fed to the linear phase detector as is the output of the 10.7 MHz center frequency VCO. The demodulator gain is typically $140\mu V/kHz$. The passive loop filter output that is comprised fully on chip is fed to both the VCO and the modulation format switch described in more detail below. This signal is representing the demodulated signal with high frequencies applied to the demodulator demodulated to logic ones and low frequencies demodulated to logic zeroes. Please note that due to this behaviour a sign inversion of the data occurs in case of high-side injection of the local oscillator at receive frequencies below 840 or 420MHz, respectively. See also .

The modulation format switch is actually a switchable amplifier with an AC gain of 11 that is controlled by the **MSEL** pin (Pin 15) as shown in the following table. This gain was chosen to facilitate detection in the subsequent circuits. The DC



gain is 1 in order not to saturate the subsequent Data Filter wih the DC offset produced by the demodulator in case of large frequency offsets of the IF signal. The resulting frequency characteristic and details on the principle of operation of the switch are described in Section 4.6.

Table 3-4 MSEL Pin Operating States	
MSEL	Modulation Format
Open	ASK
Shorted to ground	FSK

The demodulator circuit is switched off in case of reception of ASK signals.

3.4.7 Data Filter

The data filter comprises an OP-Amp with a bandwidth of 100kHz used as a voltage follower and two $100k\Omega$ on-chip resistors. Along with two external capacitors a 2nd order Sallen-Key low pass filter is formed. The selection of the capacitor values is described in Section 4.2.

3.4.8 Data Slicer

The data slicer is a fast comparator with a bandwidth of 100 kHz. This allows for a maximum receive data rate of up to 100kBaud. The maximum achievable data rate also depends on the IF Filter bandwidth and the local oscillator tolerance values. Both inputs are accessible. The output delivers a digital data signal (CMOS-like levels) for sbsequent circuits. The self-adjusting threshold on pin 20 its generated by RC-term or peak detector depending on the baseband coding scheme. The data slicer threshold generation alternatives are described in more detail in Section 4.5.

3.4.9 Peak Detector

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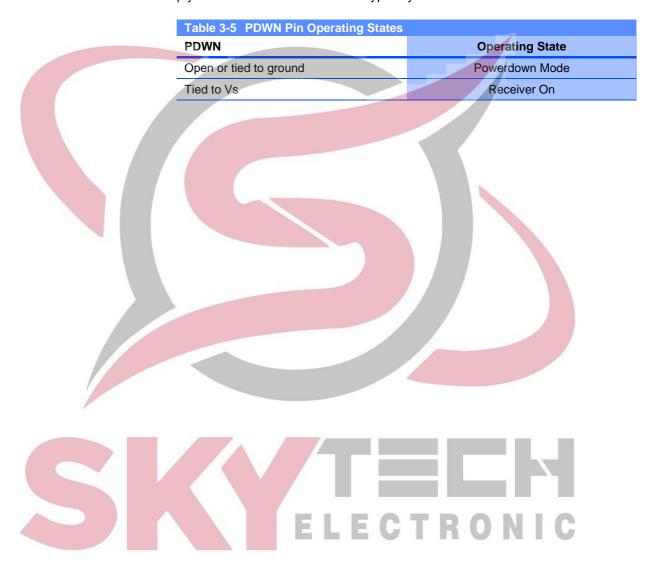
The peak detector generates a DC voltage which is proportional to the peak value of the receive data signal. An external RC network is necessary. The input is connected to the output of the RSSI-output of the Limiter, the output is connected to the **PDO** pin (Pin 26). This output can be used as an indicator for the received signal strength to use in wake-up circuits and as a reference for the data slicer in ASK mode. The maximum output current is typically 950 μ A, the discharge current is lower than 2 μ A. Note that the RSSI level is also output in case of FSK mode.





3.4.10 Bandgap Reference Circuitry

A Bandgap Reference Circuit provides a temperature stable reference voltage for the device. A power down mode is available to switch off all subcircuits which is controlled by the PWDN pin (Pin 27) as shown in the following table. The supply current drawn in this case is typically 50nA.



4 Applications

	Contents of this Chapter	
	4.1 Choice of LNA Threshold Voltage and Time Constant. 4.2 Data Filter Design. 4.3 Quartz Load Capacitance Calculation 4.4 Quartz Frequency Calculation. 4.5 Data Slicer Threshold Generation. 4.6 ASK/FSK Switch Functional Description. 4.7 Principle of the Precharge Circuit.	. 4-4 . 4-5 . 4-6 . 4-7
Śŀ	TECH ELECTRONIC	



4.1 Choice of LNA Threshold Voltage and Time Constant

In the following figure the internal circuitry of the LNA automatic gain control is shown.

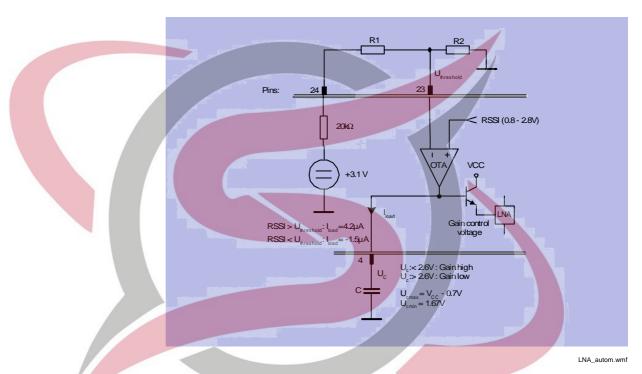


Figure 4-1 LNA Automatic Gain Control Circuitry

The LNA automatic gain control circuitry consists of an operational transimpedance amplifier that is used to compare the received signal strength signal (RSSI) generated by the Limiter with an externally provided threshold voltage Uthres. As shown in the following figure the threshold voltage can have any value between approximately 0.8 and 2.8V to provide a switching point within the receive signal dynamic range.

This voltage U_{thres} is applied to the **THRES** pin (Pin 23) The threshold voltage can be generated by attaching a voltage divider between the **3VOUT** pin (Pin 24) which provides a temperature stable 3V output generated from the internal bandgap voltage and the **THRES** pin. If the RSSI level generated by the Limiter is higher than U_{thres} , the OTA generates a positive current I_{load} . This yields a voltage rise on the **TAGC** pin (Pin 4). Otherwise, the OTA generates a negative current. These currents do not have the same values in order to achieve a fast-attack and slow-release action of the AGC and are used to charge an external capacitor which finally generates the LNA gain control voltage.



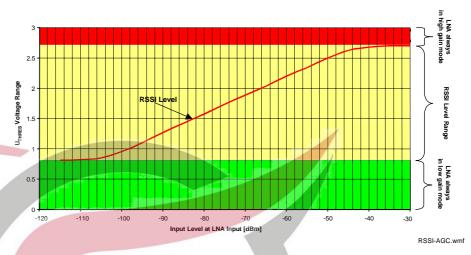


Figure 4-2 RSSI Level and Permissive AGC Threshold Levels

The switching point should be chosen according to the intended operating scenario. The determination of the optimum point is described in the accompanying Application Note, a threshold voltage level of 1.8V is apparently a viable choice. It should be noted that the output of the **3VOUT** pin is capable of driving up to $50\mu\text{A}$, but that the **THRES** pin input current is only in the region of 40nA. As the current drawn out of the **3VOUT** pin is directly related to the receiver power consumption, the power divider resistors should have high impedance values. The sum of R1 and R2 has to be $600k\Omega$ in order to yield 3V at the **3VOUT** pin. R1 can thus be chosen as $240k\Omega$, R2 as $360k\Omega$ to yield an overall **3VOUT** output current of $5\mu\text{A}^1$ and a threshold voltage of 1.8V

Note: If the LNA gain shall be kept in either high or low gain mode this has to be accomplished by tying the **THRES** pin to a fixed voltage. In order to achieve high gain mode operation, a voltage higher than 2.8V shall be applied to the **THRES** pin, such as a short to the **3VOLT** pin. In order to achieve low gain mode operation a voltage lower than 0.7V shall be applied to the **THRES**, such as a short to ground.

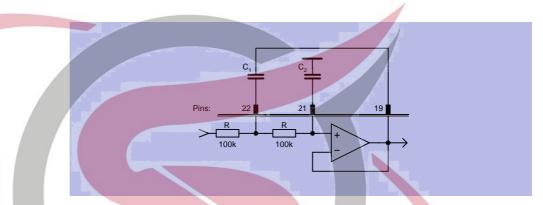
As stated above the capacitor connected to the TAGC pin is generating the gain control voltage of the LNA due to the charging and discharging currents of the OTA and thus is also responsible for the AGC time constant. As the charging and discharging currents are not equal two different time constants will result. The time constant corresponding to the charging process of the capacitor shall be chosen according to the data rate. According to measurements performed at Infineon the capacitor value should be greater than 47nF.

1. note the $20k\Omega$ resistor in series with the 3.1V internal voltage source



4.2 Data Filter Design

Utilising the on-board voltage follower and the two $100k\Omega$ on-chip resistors a 2nd order Sallen-Key low pass data filter can be constructed by adding 2 external capacitors between pins 19 (SLP) and 22 (FFB) and to pin 21 (OPP) as depicted in the following figure and described in the following formulas¹.



Filter_Design.wmf

Figure 4-3 Data Filter Design

(1)(2)

$$C1 = \frac{2Q\sqrt{b}}{R2\Pi f_{3dB}} \qquad C2 = \frac{\sqrt{b}}{4QR\Pi f_{3dB}}$$

with

$$Q = \frac{\sqrt{b}}{a}$$

(3)the quality factor of the poles

where

in case of a Bessel filter a = 1.3617, b = 0.618

and thus Q = 0.577

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and in case of a Butterworth filter a = 1.414, b = 1 and thus Q = 0.71

Example: Butterworth filter with $f_{3dB} = 5kHz$ and $R = 100k\Omega$:

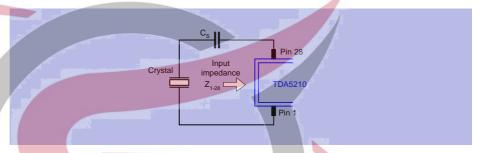
 $C_1 = 450pF, C_2 = 225pF$

1. taken from Tietze/Schenk: Halbleiterschaltungstechnik, Springer Berlin, 1999



4.3 Quartz Load Capacitance Calculation

The value of the capacitor necessary to achieve that the quartz oscillator is operating at the intended frequency is determined by the reactive part of the negative resistance of the oscillator circuit as shown in Section 5.1.3 and by the quartz specifications given by the quartz manufacturer.



Quartz_load.wm

Figure 4-4 Determination of Series Capacitance Value for the Quartz Oscillator

Crystal specified with load capacitance

$$C_s = \frac{1}{\frac{1}{C_l} + 2\pi f X_L}$$

with C_I the load capacitance (refer to the quartz crystal specification).

Examples:

6.7 MHz: $C_L = 12 \text{ pFX}_L = 695\Omega C_S = 8.9 \text{ pF}$

13.4 MHz: $C_L = 12$ pFX_L=1010 Ω C_S = 5.9 pF

These values may be obtained in high accuracy by putting two capacitors in series to the quartz, such as 22pF and 15pF in the 6.7MHz case and 22pF and 8.2pF in the 13.4MHz case.



4.4 Quartz Frequency Calculation

As described in Section 3.4.3 the operating range of the on-chip VCO is 820 to 860 MHz with a nominal center frequency of 840MHz. This signal is divided by 2 before applied to the mixer in case of operation at 434 MHz. This local oscillator signal can be used to downconvert the RF signals both with high- or low-side injection at the mixer. The resulting receive frequency ranges then extend between 810 and 870MHz or between 400 and 440MHz. Low-side injection of the local oscillator has to be used for receive frequencies between 840 and 870MHz as well as high-side injection for receive frequencies below 840MHz. Corresponding to that in the 400MHz region low-side injection is applicable for receive frequencies above 420MHz, high-side injection below this frequency. Therefore for operation both in the 868 and the 434 MHz ISM bands low-side injection of the local oscillator has to be used. Then the local oscillator frequency is calculated by subtracting the IF frequency (10.7 MHz) from the RF frequency (434 or 868 MHz). Please note that no sign-inversion occurs in case of reception and demodulation of FSK-modulated signals.

The overall division ratios in the PLL are 64 or 128 in case of operation at 868 MHz or 32 and 64 in case of operation at 434 MHz, depending on the crystal frequency used as shown below. The quartz frequency in case of low-side injection may be calculated by using the following formula:

$$f_{QU} = (f_{RF} - 10.7) / r$$

with f_{RF} receive frequency

 f_{10} local oscillator (PLL) frequency (f_{RF} - 10.7)

f_{QU} quartz oscillator frequency

ratio of local oscillator (PLL) frequency and quartz frequency as shown in the subsequent table

Table 4-1	Dependence of	PLL Overall Division Ratio	on FSEL and CSEL
FSEL		CSEL	Ratio $r = (f_{LO}/f_{QU})$
open	E	open	64
open		GND	32
GND		open	128
GND		GND	64

:

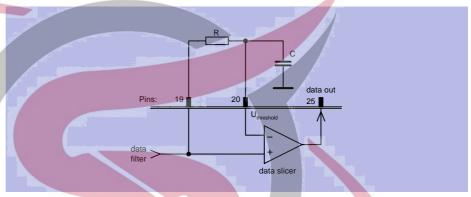
$$f_{\text{QU}} = (868.4MHz - 10.7MHz)/64 = 13.40156MHz$$

 $f_{\text{QU}} = (868.4MHz - 10.7MHz)/128 = 6.7008MHz$
 $f_{\text{QU}} = (434.2MHz - 10.7MHz)/32 = 13.23437MHz$
 $f_{\text{OU}} = (434.2MHz - 10.7MHz)/64 = 6.6172MHz$



4.5 Data Slicer Threshold Generation

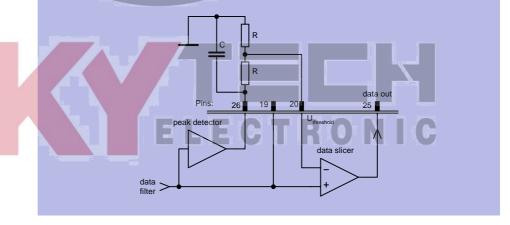
The threshold of the data slicer can be generated using an external R-C integrator as shown in Figure 4-5. The cut-off frequency of the R-C integrator has to be lower than the lowest frequency appearing in the data signal. In order to keep distortion low, the minimum value for R is $20k\Omega$.



Data_slice1.wmf

Figure 4-5 Data Slicer Threshold Generation with External R-C Integrator

In case of ASK operation another possibility for threshold generation is to use the peak detector in connection with two resistors and one capacitor as shown in the following figure. The component values are depending on the coding scheme and the protocol used.



Data_slice2.wmf

Figure 4-6 Data Slicer Threshold Generation Utilising the Peak Detector



4.6 ASK/FSK Switch Functional Description

The TDA5210 is containing an ASK/FSK switch which can be controlled via Pin 15 (MSEL). This switch is actually consisting of 2 operational amplifiers that are having a gain of 1 in case of the ASK amplifier and a gain of 11 in case of the FSK amplifier in order to achieve an appropriate demodulation gain characteristic. In order to compensate for the DC-offset generated especially in case of the FSK PLL demodulator there is a feedback connection between the threshold voltage of the bit slicer comparator (Pin 20) to the negative input of the FSK switch amplifier. This is shown in the following figure.

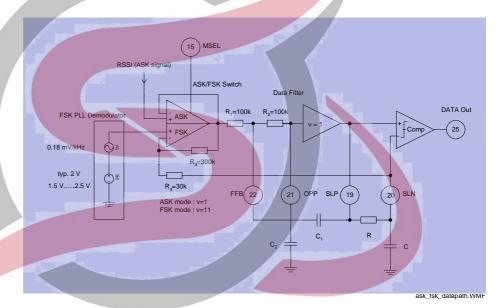


Figure 4-7 ASK/FSK mode datapath

4.6.1 FSK Mode

The FSK datapath has a bandpass characterisite due to the feedback shown above (highpass) and the data filter (lowpass). The lower cutoff frequency f2 is determined by the external RC-combination. The upper cutoff frequency f3 is determined by the data filter bandwidth.

The demodulation gain of the FSK PLL demodulator is $140\mu V/kHz$. This gain is increased by the gain v of the FSK switch, which is 11. Therefore the resulting dynamic gain of this circuit is 2mV/kHz within the bandpass. The gain for the DC content of FSK signal remains at $140\mu V/kHz$. The cutoff frequencies of the bandpass have to be chosen such that the spectrum of the data signal is influenced in an acceptable amount.

In case that the user data is containing long sequences of logical zeroes the effect of the drift-off of the bit slicer threshold voltage can be lowered if the offset voltage inherent at the negative input of the slicer comparator (Pin20) is used. The comparator has no hysteresis built in.

Applications

This offset voltage is generated by the bias current of the negative input of the comparator (i.e. 20nA) running over the external resistor R. This voltage raises the voltage appearing at pin 20 (e.g. 1mV with R = $100k\Omega$). In order to obtain benefit of this asymmetrical offset for the demodulation of long zeros the lower of the two FSK frequencies should be chosen in the transmitter as the zero-symbol frequency.

In the following figure the shape of the above mentioned bandpass is shown.

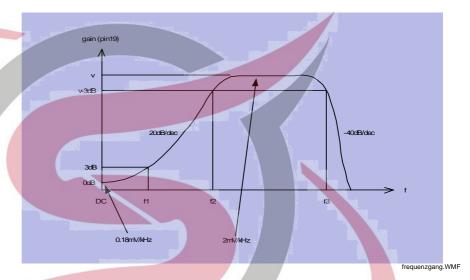


Figure 4-8 Frequency characterstic in case of FSK mode

The cutoff frequencies are calculated with the following formulas:

$$f_{1} = \frac{1}{2\pi \frac{R \cdot 330k\Omega}{R + 330k\Omega} \cdot C}$$

$$f_{2} = v \cdot f_{1} = 11 \cdot f_{1}$$
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$$f_{3} = f_{3dB}$$

f₃ is the 3dB cutoff frequency of the data filter - see Section 4.2.

Example:

 $R=100k\Omega,\,C=47nF$

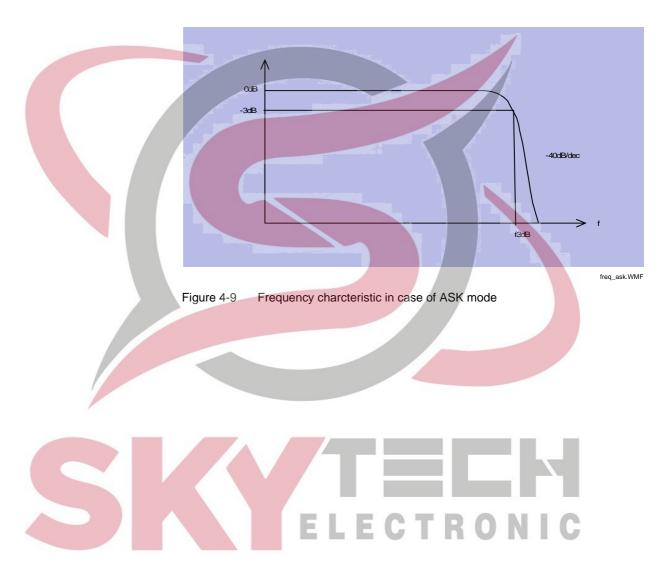
This leads $tof_1 = 44Hzandf_2 = 485Hz$



Applications

4.6.2 ASK Mode

In case the receiver is operated in ASK mode the datapath frequency charactersitic is dominated by the data filter alone, thus it is lowpass shaped. The cutoff frequency is determined by the external capacitors C12 and C14 and the internal 100k resistors as described in Section 4.2





4.7 Principle of the Precharge Circuit

In case the data slicer threshold shall be generated with an external RC network as described in Section 4.5 it is necessary to use large values for the capacitor C attached to the **SLN** pin (pin 20) in order to achieve long time constants. This results also from the fact that the choice of the value for R connected between the **SLP** and **SLN** pins (pins 19 and 20) is limited by the $330 \mathrm{k}\Omega$ resistor appearing in parallel to R as can be seen in Figure 4-7. Apart from this a resistor value of $100 \mathrm{k}\Omega$ leads to a voltage offset of 1mv at the comparator input as described in Section 4.6.1. The resulting startup time constant τ_1 can be calculated with:

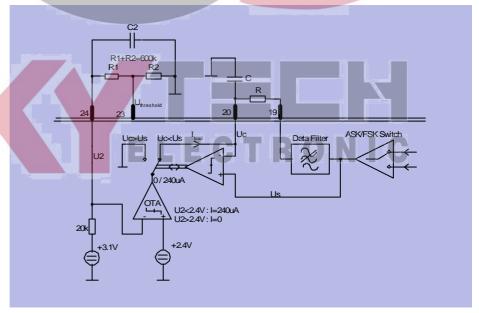
$$\tau_1 = (R // 330k\Omega) \cdot C$$

In case R is chosen to be $100k\Omega$ and C is chosen as 47nF this leads to

$$\tau_1 = (100k\Omega // 330k\Omega) \cdot 47nF = 77k\Omega \cdot 47nF = 3.6ms$$

When the device is turned on this time constant dominates the time necessary for the device to be able to demodulate data properly. In the powerdown mode the capacitor is only discharged by leakage currents.

In order to reduce the turn-on time in the presence of large values of C a precharge circuit was included in the TDA5210 as shown in the following figure.



precharge.WMF

Figure 4-10 Principle of the precharge circuit

Applications

This circuit charges the capacitor C with an inrush current I_{load} of typically 220µA for a duration of T_2 until the voltage U_c appearing on the capacitor is equal to the voltage U_s at the input of the data filter. This voltage is limited to 2.5V. As soon as these voltages are equal or the duration T_2 is exceeded the precharge circuit is disabled.

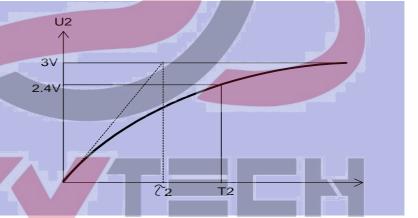
 τ_2 is the time constant of the charging process of C which can be calculated as

$$\tau_2 \approx 20 k\Omega \cdot C2$$

as the sum of R1 and R2 is sufficiently large and thus can be neglected. T2 can then be calculated according to the following formula:

$$T_2 = \tau_2 \ln \left(\frac{1}{1 - \frac{2.4V}{3V}} \right) \approx \tau_2 \cdot 1.6$$

The voltage transient during the charging of C2 is shown in the following figure:



e-fkt1.WMF

Figure 4-11 Voltage appearing on C2 during precharging process

The voltage appearing on the capacitor C connected to pin 20 is shown in the following figure. It can be seen that due to the fact that it is charged by a constant current source it exhibits is a linear increase in voltage which is limited to $U_{Smax} = 2.5V$ which is also the approximate operating point of the data filter input. The time constant appearing in this case can be denoted as T3, which can be calculated with

$$T3 = \frac{U_{\text{Smax}} \cdot C}{220 \mu A} = \frac{2.5 \text{ V}}{220 \mu A} \cdot C$$

Applications

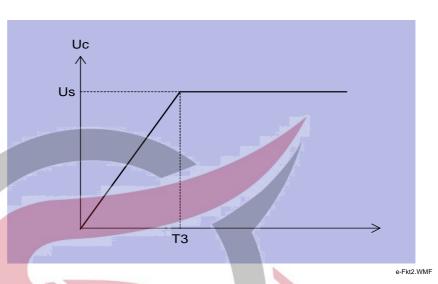


Figure 4-12 Voltage transient on capacitor C attached to pin 20

As an example the choice of $C_2 = 22nF$ and C = 47nF yields

 $\tau_2 = 0.44 \text{ms}$

 $T_2 = 0.71 \text{ms}$

 $T_3 = 0.53 ms$

This means that in this case the inrush current could flow for a duration of 0.64ms but stops already after 0.49ms when the U_{Smax} limit has been reached. T3 should always be chosen to be shorter than T2.

It has to be noted finally that during the turn-on duration T2 the overall device power consumption is increased by the 220µA needed to charge C.

The precharge circuit may be disabled if C2 is not equipped. This yields a T2 close to zero. Note that the sum of R4 and R5 has to be $600k\Omega$ in order to produce 3V at the THRES pin as this voltage is internally used also as the reference for the FSK demodulator.

5 Reference

	Contents of this Chapter	
	5.1 Electrical Data. 5.2 Test Circuit 5.3 Test Board Layouts. 5.4 Bill of Materials	5-12 5-13
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Reference

5.1 Electrical Data

5.1.1 Absolute Maximum Ratings



WARNING

The maximum ratings may not be exceeded under any circumstances, not even momentarily and individually, as permanent damage to the IC will result.

Table 5-1 Absolute Maximum Ratings, Ambient temperature T _{AMB} =-40°C + 105°C						
#	Parameter	Symbol	Limit Values		Unit	Remarks
			min	max		
1	Supply Voltage	V _s	-0.3	5.5	V	
2	Junction Temperature	Tj	-40	+150	°C	
3	Storage Temperature	T _s	-40	+125	°C	
4	Thermal Resistance	R _{thJA}		114	K/W	
5	ESD integrity, all pins excl. Pins 1,3, 6, 28 ESD integrity Pins 1,3,6,28	V _{ESD}		+2 +1.5	kV kV	HBM according to MIL STD 883D, method 3015.7





5.1.2 Operating Range

Within the operational range the IC operates as explained in the circuit description. The AC/DC characteristic limits are not guaranteed. Currents flowing into the device are denoted as positive currents and v.v.

Supply voltage: VCC = 4.5V .. 5.5V

Tal	ole 5-2 Operating Range, A	mbient tempe	erature T	MP= -40°	C + 10	05°C		
#	Parameter	Symbol	Limit \		Unit	Test Conditions	L	Item
			min	max				
1	Supply Current	I _{SF 868}	4.1	7.7	mΑ	f _{RF} = 868MHz, FSK Mode		
		I _{SF 434}	3.9	7.5	mA	f _{RF} = 434MHz, FSK Mode		
		I _{SA 868}	3.4	7	mΑ	f _{RF} = 868MHz, ASK Mode		
		I _{SA 434}	3.2	6.8	mA	f _{RF} = 434MHz, ASK Mode		
2	Receiver Input Level ASK FSK, frequ. dev. ± 50kHz	RF _{in}	-106 -100	-13 -13	dBm dBm	@ source impedance 50Ω, BER 2E-3, average power level, Manchester encoded datarate 4kBit, 280kHz IF Bandwidth	•	
3	LNI Input Frequency	f _{RF}	400/ 810	440/ 870	MHz			
4	MI/X Input Frequency	f _{MI}	400/ 810	440/ 870	MHz			
5	3dB IF Frequency Range ASK FSK	f _{IF -3dB}	5 10.4	23 11	MHz		•	
6	Powerdown Mode On	PWDN _{ON}	0	0.8	V			
7	Powerdown Mode Off	PWDN _{OFF}	2	V _S	V			
8	Gain Control Voltage, LNA high gain state	V _{THRES}	2.8	Vs	V			
9	Gain Control Voltage, LNA low gain state	V _{THRES}	0=	0.7	ď	TRONIC		

■ This value is guaranteed by design.



5.1.3 AC/DC Characteristics at T_{AMB} = 25°C

AC/DC characteristics involve the spread of values guaranteed within the specified voltage and ambient temperature range. Typical characteristics are the median of the production. Currents flowing into the device are denoted as positive currents and vice versa.

Та	ble 5-3 AC/DC Character	istics with T _f	25 °C, V	_{VCC} = 4.5	5.5 V				
	Parameter	Symbol	100000	imit Valu	es	Unit	Test Conditions	L	Item
			min	typ	max		5/		
Su	pply								
Su	pply Current								
1	Supply current, standby mode	I _{S PDWN}		50	100	nA	Pin 27 (PDWN) open or tied to 0 V		
2	Supply current, device operating in 868 MHz range, FSK mode	I _{SF 868}	5.1	5.9	6.7	mA	Pin 11 (FSEL) tied to GND, Pin 15 (MSEL) tied to GND		
3	Supply current, device operating in 434 MHz range, FSK mode	I _{SF 434}	4.9	5.7	6.5	mA	Pin 11 (FSEL) open, Pin 15 (MSEL) tied to GND		
4	Supply current, device operating in 868 MHz range, ASK mode	I _{SA 868}	4.4	5.2	6	mA	Pin 11 (FSEL) tied to GND, Pin 15 (MSEL) open		
5	Supply current, device operating in 434 MHz range, ASK mode	I _{SA 434}	4.2	5	5.8	mA	Pin 11 (FSEL) open, Pin 15 (MSEL) open		
	rango, non modo						(WOLL) opon		

LNA

Signal Input LNI (PIN 3), V_{THRES} > 2.8V, high gain mode

1	Average Power Level at BER = 2E-3 (Sensitivity) ASK	RFin	V	-110		dBm	Manchester encoded datarate 4kBit, 280kHz IF Bandwidth	•	
2	Average Power Level at BER = 2E-3 (Sensitivity) FSK	RF _{in}		-103	E C'	dBm	Manchester enc. datarate 4kBit, 280kHz IF Bandw., ± 50kHz pk. dev.	•	
3	Input impedance, f _{RF} =434 MHz	S _{11 LNA}	0.8	373 / -34.7	deg			•	
4	Input impedance, f _{RF} =869 MHz	S _{11 LNA}	0.7	'38 / -73.5	deg			•	
5	Input level @ 1dB compression	P1dB _{LNA}		-15		dBm			
6	Input 3 rd order intercept point f _{RF} =434 MHz	IIP3 _{LNA}		-10		dBm	matched input		
7	Input 3 rd order intercept point f _{RF} =869 MHz	IIP3 _{LNA}		-14		dBm	matched input		



Tal	ble 5-3 AC/DC Character	istics with T _A	25 °C, V	_{VCC} = 4.5	5.5 V (d	continue	d)		
	Parameter	Symbol	ı	₋imit Valu	es	Unit	Test Conditions	L	Item
			min	typ	max				
8	LO signal feedthrough at antenna port	LO _{LNI}			-73	dBm		•	
Sig	gnal Output LNO (PIN 6),	V _{THRES} > 2.8	V, high g	ain mode					
1	Gain f _{RF} =434 MHz	S _{21 LNA}	1.5	509 / 138.2	deg				
2	Gain f _{RF} =869 MHz	S _{21 LNA}	1.4	19 / 101.7	' deg				
3	Output impedance, f _{RF} =434 MHz	S _{22 LNA}	0.8	386 / -12.9	deg			ľ	
4	Output impedance, f _{RF} =869 MHz	S _{22 LNA}	3.0	366 / -24.2	deg			ŀ	
5	Voltage Gain Antenna to IFO f _{RF} =434 MHz	G _{AntMI}		42		dB			
6	Voltage Gain Antenna to IFO f _{RF} =869 MHz	G _{AntMI}	7	40	-	dB			
Sig	gnal Input LNI, V _{THRES} =	GND, low gair	n mode						
1	Input impedance, f _{RF} =434 MHz	S _{11 LNA}	3.0	373 / -34.7	deg			·	
2	Input impedance, f _{RF} =869 MHz	S _{11 LNA}	0.7	738 / -73.5	deg	47		•	
3	Input level @ 1dB C. P f _{RF} = 434 MHz	P1dB _{LNA}		-18		dBm	matched input	•	
4	Input level @ 1dB C. P f _{RF} = 869 MHz	P1dB _{LNA}		-6		dBm	matched input	•	
5	Input 3 rd order intercept point f _{RF} =434 MHz	IIP3 _{LNA}	_	-10		dBm	matched input	۰	
6	Input 3 rd order intercept point f _{RF} =869 MHz	IIP3 _{LNA}	V	-5		dBm	matched input	•	
Sig	gnal Output LNO, V _{THRES}	= GND, low g	gain mod	le					
1	Gain f _{RF} =434 MHz	S _{21 LNA}	0.1	83 / 140.6	deg	TR			
2	Gain f _{RF} =869 MHz	S _{21 LNA}	0.	179 / 109.	Ideg			•	
3	Output impedance, f _{RF} =434 MHz	S _{22 LNA}	3.0	397 / -13.6			•		
4	Output impedance, f _{RF} =869 MHz	S _{22 LNA}	0.8	368 / -26.3	deg			•	
5	Voltage Gain Antenna to MI f _{RF} =434 MHz	G _{AntMI}		22		dB			
6	Voltage Gain Antenna to MI f _{RF} =869 MHz	G _{AntMI}		19		dB			



Tal	Table 5-3 AC/DC Characteristics with T _A 25 °C, V _{VCC} = 4.5 5.5 V (continued)									
	Parameter	Symbol	L	_imit Valu	es	Unit	Test Conditions	L	Item	
			min	typ	max					
Sig	nal 3VOUT (PIN 24)									
1	Output voltage	V _{3VOUT}	2.9	3.1	3.3	V	3VOUT Pin open			
2	Current out	I _{3VOUT}	-3	-5	-10	μA	see Section 4.1			
Sig	gnal THRES (PIN 23)									
1	Input Voltage range	V _{THRES}	0		V _S -1V	V	see Section 4.1			
2	LNA low gain mode	V _{THRES}	0			V				
3	LNA high gain mode	V _{THRES}	2.8	3	V _S	V	or shorted to Pin 24			
4	Current in	I _{THRES_in}		5		nA	A			
Sig	gnal TAGC (PIN 4)									
1	Current out, LNA low gain state	I _{TAGC_out}	-3.6	-4.2	-5	μΑ	RSSI > V _{THRES}			
2	Current in, LNA high gain state	V _{TAGC_in}	1	1.6	2.2	μA	RSSI>V _{THRES}			
MIX	XER									
Sig	Signal Input MI/MIX (PINS 8/9)									
1	Input impedance, f _{RF} =434 MHz	S _{11 MIX}	0.9	942 / -14.4	deg	47		•		
2	Input impedance, f _{RF} =869 MHz	S _{11 MIX}	0.9	918 / -28.1	deg	/-		•		
3	Input 3 rd order intercept point f _{RF} =434 MHz	IIP3 _{MIX}	No.	-28	A 1	dBm		•		
4	Input 3 rd order intercept point f _{RF} =869 MHz	IIP3 _{MIX}	-	-26		dBm		•		
Sig	gnal Output IFO (PIN 12)	$\mathcal{T}A$								
1	Output impedance	Z _{IFO}	A	330		Ω				
2	Conversion Voltage Gain f _{RF} =434 MHz	G _{MIX}		+19	E (G)	dB	ONIC			
3	Conversion Voltage Gain f _{RF} =869 MHz	G _{MIX}		+18		dB				
LIN	MITER									
Sig	gnal Input LIM/X (PINS 17	/18)								
1	Input Impedance	Z_{LIM}	264	330	396	Ω				
2	RSSI dynamic range	DR _{RSSI}	60		80	dB				
3	RSSI linearity	LIN _{RSSI}		±1		dB		•		
4	Operating frequency (3dB points)	f _{LIM}	5	10.7	23	MHz		•		



	Parameter	Symbol		Limit Valu	es	Unit	Test Conditions	L	Item
			min	typ	max				
DΑ	ATA FILTER								
1	Useable bandwidth	BW _{BB FILT}			100	kHz			
2	RSSI Level at Data Filter Output SLP, RF _{IN} =-103dBm	RSSI _{low}	0.3		1	V	LNA in high gain mode		
3	RSSI Level at Data Filter Output SLP, RF _{IN} =-30dBm	RSSI _{high}	1.8		3	V	LNA in high gain mode		
Sli	cer, Signal Output DATA	(PIN 25)							
1	Maximum Datarate	DR _{max}			100	kBps	NRZ, 20pF capacitive loading	•	
2	LOW output voltage	V _{SLIC_L}	0		0.1	V			
3	HIGH output voltage	V _{SLIC_H}	V _S - 1.3V	V _S -1V	V _S - 0.7V	V			
Sli	cer, Signal Output DATA	(PIN 20)							
1	Precharge Current Out	I _{PCH_SLN}	-100	-220	-300	μA	see Section 4.7		
PE	AK DETECTOR					/-7			
Siç	gnal Output PDO (PIN 26)								
1	Load current	l _{load}	-600	-950	-1300	μΑ			
2	Leakage current	I _{leakage}	0	200	1000	nA			
CF	RYSTAL OSCILLATOR								
Siç	gnals CRSTL1, CRSTL 2,	(PINS 1/28)							
1	Operating frequency	fCRSTL	6		14	MHz	fundamental mode, series resonance		
2	Input Impedance @ ~6MHz	Z ₁₋₂₈		-825 +j695		Ω		•	
3	Input Impedance @ ~13MHz	Z ₁₋₂₈		-600 +j1010	E C	Ω	ONIC	•	
4	Serial Capacity @ ~6MHz	C _{S 6} =C1		8.9		pF			
5	Serial Capacity @ ~13MHz	C _{S13} =C1		5.9		pF			
AS	K/FSK Signal Switch								
	gnal MSEL (PIN 15)								
1	ASK Mode	V _{MSEL}	1.4		4	V	or open		
2	FSK Mode	V _{MSEL}	0		0.2	V			



	Parameter	Symbol	L	imit Valu	es	Unit	Test Conditions	L	Item
			min	typ	max				
FS	K DEMODULATOR								
1	Demodulation Gain	G _{FMDEM}	85	140	225	μV/ kHz			
2	Useable IF Bandwidth	BW _{IFPLL}	10.2	10.7	11.2	MHz			
PÇ	WER DOWN MODE								
Sig	nal PDWN (PIN 27)								
1	Powerdown Mode On	PWDN _{ON}	0		0.8	V	A STATE OF THE STA		
2	Powerdown Mode Off	PWDN _{Off}	2.8	77.53	Vs	V	A CONTRACTOR OF THE PARTY OF TH		
3	Input bias current PDWN	I _{PDWN}		19		uA	Power On Mode		
4	Start-up Time until valid signal is detected at IF	T _{SU}	7		1	ms			
VC	O MULTIPLEXER								
Siç	nal FSEL (PIN 11)								
1	f _{RF} range 434 MHz	V _{FSEL}	1.4		4	V	or open		
2	f _{RF} range 869 MHz	V _{FSEL}	0		0.2	V		١,	
3	Output bias current FSEL	I _{FSEL}	-160	-200	-240	μA	FSEL tied to GND		
PL	L DIVIDER								
Siç	nal CSEL (PIN 16)	9500			ASS.				
1	f _{CRSTL} range 6.xxMHz	V _{CSEL}	1.4		4	V	or open		
2	f _{CRSTL} range 13.xxMHz	V _{CSEL}	0		0.2	V			
3	Input bias current CSEL	I _{CSEL}	-3	-5	-7	μA	CSEL tied to GND		



5.1.4 AC/DC Characteristics at T_{AMB} = -40 to 105°C

Currents flowing into the device are denoted as positive currents and vice versa

	Parameter	Symbol	ı	Limit Valu	ies	Unit	Test Conditions	L	Item
			min	typ	max				
Su	ipply								
Su	pply Current						1		
1	Supply current, standby mode	S PDWN		50	400	nA	Pin 27 (PDWN) open or tied to 0 V		
2	Supply current, device operating in 868 MHz range, FSK mode	I _{SF 868}	4.1	5.9	7.7	mA	Pin 11 (FSEL) tied to GND, Pin 15 (MSEL) tied to GND		
3	Supply current, device operating in 434 MHz range, FSK mode	I _{SF 434}	3.9	5.7	7.5	mA	Pin 11 (FSEL) open, Pin 15 (MSEL) tied to GND		
4	Supply current, device operating in 868 MHz range, ASK mode	I _{SA 868}	3.4	5.2	7	mA	Pin 11 (FSEL) tied to GND, Pin 15 (MSEL) open		
5	Supply current, device operating in 434 MHz range, ASK mode	I _{SA 434}	3.2	5	6.8	mA	Pin 11 (FSEL) open, Pin 15 (MSEL) open		
Się	gnal 3VOUT (PIN 24)								
1	Output voltage	V _{3VOUT}	2.9	3.1	3.3	V	3VOUT Pin open		
2	Current out	I _{3VOUT}	-3	-5	-10	μA	see Section 4.1		
Się	gnal THRES (PIN 23)								
1	Input Voltage range	V _{THRES}	0		V _S -1V	V	see Section 4.1		
2	LNA low gain mode	V_{THRES}	0		0.3	V			
3	LNA high gain mode	V _{THRES}	3		V _S	V	or shorted to Pin 24		
4	Current in	I _{THRES_in}		5		nA			
Sig	gnal TAGC (PIN 4)								
1	Current out, LNA low gain state	I _{TAGC_out}	-1	-4.2	-8 E O 1	μA	RSSI > V _{THRES}		
2	Current in, LNA high gain state	V _{TAGC_in}	0.5	1.5	5	μA	RSSI>V _{THRES}		
ΜI	XER								
1	Conversion Voltage Gain f _{RF} =434 MHz	G _{MIX}		+19		dB			
2	Conversion Voltage Gain f _{RF} =869 MHz	G _{MIX}		+18		dB			
	MITER								
Się	gnal Input LIM/X (PINS 17	/18)							
1	RSSI dynamic range	DR _{RSSI}	60		80	dB			



ıa	ble 5-4 AC/DC Character	istics with IA	MB = -40 `	C + 10	o'C, V _{VCC}	= 4.5	0.5 V		
	Parameter	Symbol	l	_imit Valu	es	Unit	Test Conditions	L	Iten
			min	typ	max				
DΑ	TA FILTER								
2	RSSI Level at Data Filter Output SLP, RF _{IN} =-103dBm	RSSI _{low}	0.3		1	V	LNA in high gain mode		
3	RSSI Level at Data Filter Output SLP, RF _{IN} =-30dBm	RSSI _{high}	1.8		3	V	LNA in high gain mode		
Sli	cer, Signal Output DATA	(PIN 25)					1		
1	Maximum Datarate	DR _{max}			100	kBps	NRZ, 20pF capacitive loading	•	
2	LOW output voltage	V _{SLIC_L}	0		0.1	V	A		
3	HIGH output voltage	V _{SLIC_H}	V _S - 1.5V	V _S -1V	V _S - 0.5V	V			
Sli	c <mark>er, Signal</mark> Output DATA	(PIN 20)							
1	Precharge Current Out	I _{PCH_SLN}	-100	-220	-300	μA	see Section 4.7		
	AK DETECTOR								
Siç	gnal Output PDO (PIN 26)								
1	Load current	I _{load}	-400	-850	-1400	μA			
2	Leakage current	leakage	0	700	2000	nA			
CR	YSTAL OSCILLATOR		The state of the s						
Się	gnals CRSTL1, CRSTL 2,	(PINS 1/28)							
1	Operating frequency	f _{CRSTL}	6		14	MHz	fundamental mode, series resonance		
AS	K/FSK Signal Switch								
Siç	gnal MSEL (PIN 15)								
1	ASK Mode	V _{MSEL}	1.4		4	V	or open		
2	FSK Mode	V _{MSEL}	0		0.2	V			
FS	K DEMODULATOR				EC	T D	ONIC		
1	Demodulation Gain	G _{FMDEM}	105	140	245	μV/ kHz	- V-III-V		
2	Useable IF Bandwidth	BW _{IFPLL}	10.2	10.7	11.2	MHz			
PC	WER DOWN MODE								
Siç	gnal PDWN (PIN 27)								
1	Powerdown Mode On	PWDN _{ON}	0		0.8	V			
2	Powerdown Mode Off	PWDN _{Off}	2.8		٧ _S	V			
_									



Та	Table 5-4 AC/DC Characteristics with T _{AMB} = -40°C + 105°C, V _{VCC} = 4.5 5.5 V									
	Parameter	Symbol	L	imit Valu	es	Unit	Test Conditions	L	Item	
			min	typ	max					
VC	O MULTIPLEXER									
Sig	Signal FSEL (PIN 11)									
1	f _{RF} range 434 MHz	V_{FSEL}	1.4		4	V	or open			
2	f _{RF} range 869 MHz	V_{FSEL}	0		0.2	V				
3	Output bias current	I _{FSEL}	-110	-200	-340	μA	FSEL tied to GND			
-4	FSEL						*			
PL	L DIVIDER									
Sig	gnal CSEL (PIN 16)									
1	f _{CRSTL} range 6.xxMHz	V _{CSEL}	1.4		4	V	or open			
2	f _{CRSTL} range	V _{CSEL}	0		0.2	V				
	13.xxMHz									
3	Input bias current CSEL	ICSEL	-3	-5	-7	μA	CSEL tied to GND			





5.2 Test Circuit

The device performance parameters marked with ■ in Section 5.1.3 were measured on an Infineon evaluation board. This evaluation board can be obtained together with evaluation boards of the accompanying transmitter device TDA5100 in an evaluation kit that may be ordered on the INFINEON RKE Webpage www.infineon.com/rke. In case a matching codeword is received, decoded and accepted by the decoder the on-board LED will turn on. This signal is also accessible on a 2-pole pin connector and can be used for simple remote-control applications. More information on the kit is available on request.

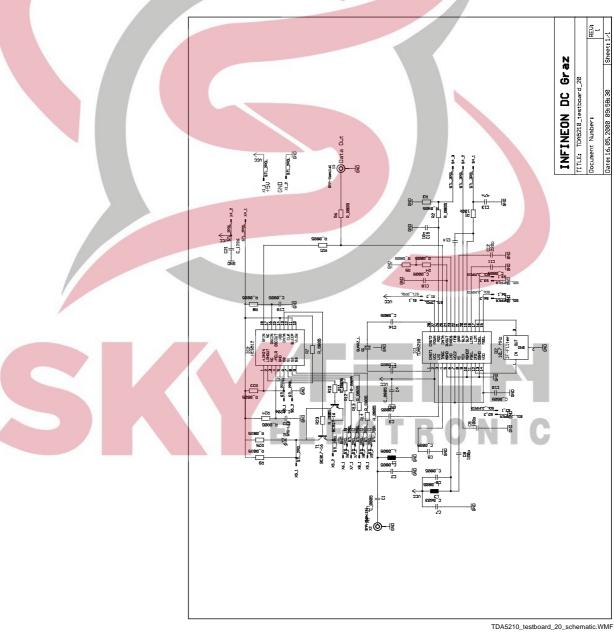
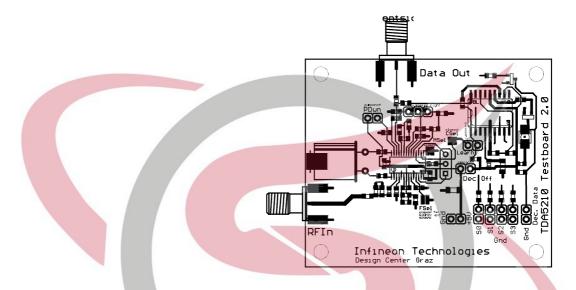


Figure 5-1 Schematic of the Evaluation Board

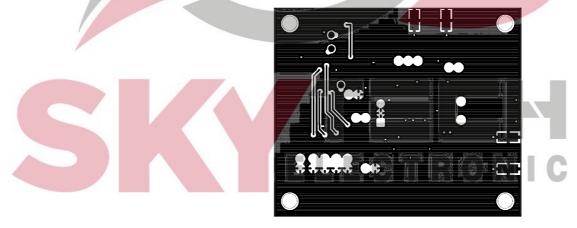


5.3 Test Board Layouts



tda5210_testboard_20_top.WMF

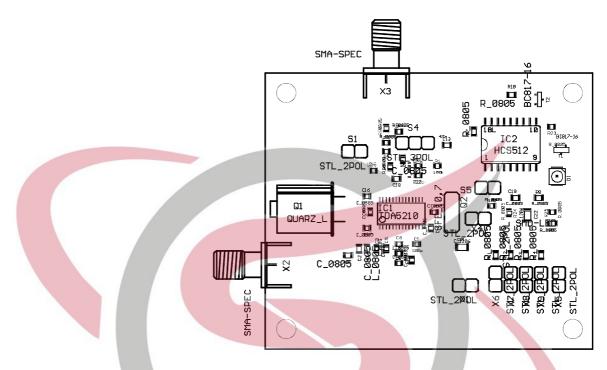
Figure 5-2 Top Side of the Evaluation Board



tda5210_testboard_20_bot.WMF

Figure 5-3 Bottom Side of the Evaluation Board





tda5210_testboard_20_plc.EMF

Figure 5-4 Component Placement on the Evaluation Board

SITECH



5.4 Bill of Materials

The following components are necessary for evaluation of the TDA5210 without use of a Microchip HCS512 decoder.

Table 5-5 Bill o	of Materials	
Ref	Value	Specification
R1	100kΩ	0805, ± 5%
R2	100kΩ	0805, ± 5%
R3	820kΩ	0805, ± 5%
R4	240kΩ	0805, ± 5%
R5	360kΩ	0805, ± 5%
R6	10kΩ	0805, ± 5%
L1	434 MHz: 15nH 869 MHz: 3.3nH	Toko, PTL2012-F15N0G Toko, PTL2012- <mark>F3</mark> N3C
L2	434 MHz: <mark>8.2pF</mark> 869 MHz: 3.9nH	0805, COG, ± 0.1pF Toko, PTL2012-F3N9C
C1	1pF	0805, COG, ± 0.1pF
C2	434 MHz: 4.7pF 869 MHz: 3.9pF	0805, COG, ± 0.1pF 0805, COG, ± 0.1pF
C3	434 MHz: 6.8pF 869 MHz: 5.6pF	0805, COG, ± 0.1pF 0805, COG, ± 0.1pF
C4	100pF	0805, COG, ± 5%
C5	47nF	1206, X7R, ± 10%
C6	434 MHz: 10nH 869 MHz: 3.9pF	Toko, PTL2012-F10N0G 0805, COG, ± 0.1pF
C7	100pF	0805, COG, ± 5%
C8	434 MHz: 33pF 869 MHz: 22pF	0805, COG, ± 5% 0805, COG, ± 5%
C9	100pF	0805, COG, ± 5%
C10	10nF	0805, X7R, ± 10%
C11	10nF	0805, X7R, ± 10%
C12	220pF	0805, COG, ± 5%
C13	47nF	0805, X7R, ± 10%
C14	470pF	0805, COG, ± 5%
C15	47nF	0805, X7R, ± 5%
C16	8.2pF	0805, COG, ± 0.1pF
C17	22pF	0805, COG, ± 1%
C18	22nF	0805, X7R, ± 5%
Q1	(f _{RF} – 10.7MHz)/32 or (f _{RF} – 10.7MHz)/64	HC49/U, fundamental mode, CL = 12pF, e.g. 434.2MHz: Jauch Q 13,23437-S11-1323-12-10/20 e.g. 868.4MHz: Jauch Q 13,40155-S11-1323-12-10/20



Q2	SFE10.7MA5-A or SKM107M1-A20-10	Murata Toko
X2, X3	142-0701-801	Johnson
S1-S3, S6 X1, X3		2-pole pin connector
S4		3-pole pin connector, or not equipped
IC1	TDA 5210	Infineon

Please note that in case of operation at 434 MHz a capacitor has to be soldered in place L2 and an inductor in place C6.

The following components are necessary in addition to the above mentioned ones for evaluation of the TDA5210 in conjunction with a Microchip HCS512 decoder.

Table 5-6 Bill o	of Materials Addendum	
Ref	Value	Specification
R7	100kΩ	0805, ± 5%
R8	10kΩ	0805, ± 5%
R9	100kΩ	0805, ± 5%
R10	22kΩ	0805, ± 5%
R11	100Ω	0805, ± 5%
R12	100Ω	0805, ± 5%
R13	100Ω	0805, ± 5%
R14	100Ω	0805, ± 5%
R21	22kΩ	0805, ± 5%
R22	10kΩ	0805, ± 5%
R23	22kΩ	0805, ± 5%
R24	820kΩ	0805, ± 5%
R25	560Ω	0805, ± 5%
C19	10pF	0805, COG, ± 5%
C21	100nF	1206, X7R, ± 10%
C22	100nF	1206, X7R, ± 10%
IC2	HCS512	Microchip
S5, X4-X9		2-pole pin connector
T1, T2	BC 847B	Infineon
D1	LS T670-JL	Infineon







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